

ABSTRACT

A probe for an electrical connection apparatus includes: a foot portion having an elongated shape extending in a first direction, and having a joint portion that joins to a probe substrate; an arm support portion including a support member extending in a direction intersecting the first direction in the vicinity of one end portion of the foot portion, and a diagonal member that couples from any point on the support member to a point between the other end portion and the center of the foot portion; and a cantilever-structured arm portion having a fixed end and a free end, in which a contact portion that comes into contact with an inspection object is formed at a tip of the free end and the fixed end is coupled to the arm support portion.

FIG. 1